



# FQD13N06 / FQU13N06

#### **60V N-Channel MOSFET**

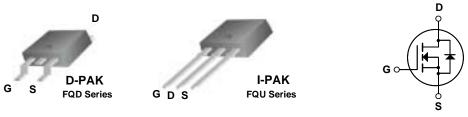
### **General Description**

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for low voltage applications such as DC/DC converters, high efficiency switching for power management in portable and battery operated products.

#### **Features**

- 10A, 60V,  $R_{DS(on)} = 0.14\Omega @V_{GS} = 10 \text{ V}$
- Low gate charge (typical 5.8 nC)
- Low Crss (typical 15 pF)
- Fast switching
- 100% avalanche tested
- · Improved dv/dt capability



# Absolute Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

Symbol	Parameter		FQD13N06 / FQU13N06	Units	
V <sub>DSS</sub>	Drain-Source Voltage		60	V	
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°C	)	10	А	
	- Continuous (T <sub>C</sub> = 100°	C)	6.3	А	
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	40	Α	
V <sub>GSS</sub>	Gate-Source Voltage		± 25	V	
E <sub>AS</sub>	Single Pulsed Avalanche Energy	(Note 2)	85	mJ	
I <sub>AR</sub>	Avalanche Current	(Note 1)	10	А	
E <sub>AR</sub>	Repetitive Avalanche Energy	(Note 1)	2.8	mJ	
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	7.0	V/ns	
P <sub>D</sub>	Power Dissipation (T <sub>A</sub> = 25°C) *		2.5	W	
	Power Dissipation (T <sub>C</sub> = 25°C)		28	W	
	- Derate above 25°C		0.22	W/°C	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	°C	
T <sub>L</sub>	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C	

#### **Thermal Characteristics**

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		4.5	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *		50	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		110	°C/W

<sup>\*</sup> When mounted on the minimum pad size recommended (PCB Mount)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	racteristics					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	60			V
$\Delta BV_{DSS}$ / $\Delta T_J$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, Referenced to 25°C		0.06		V/°C
I <sub>DSS</sub>	Zana Cata Valta na Dunia Commant	V <sub>DS</sub> = 60 V, V <sub>GS</sub> = 0 V			1	μΑ
	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 48 V, T <sub>C</sub> = 125°C			10	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 25 V, V <sub>DS</sub> = 0 V			100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	$V_{GS} = -25 \text{ V}, V_{DS} = 0 \text{ V}$		1	-100	nA
On Cha	racteristics					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	2.0		4.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 5.0 A		0.11	0.14	Ω
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = 25 \text{ V}, I_{D} = 5.0 \text{ A}$ (Note 4)		4.9		S
	Input Capacitance Output Capacitance	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V, f = 1.0 MHz		240 90	310 120	pF pF
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 25 \text{ V. } V_{GS} = 0 \text{ V.}$		240	310	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	f = 1.0 MHz		15	20	рF
Switchi	ng Characteristics					
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = 30 V, I <sub>D</sub> = 6.5 A,		5	20	ns
t <sub>r</sub>	Turn-On Rise Time	$R_G = 25 \Omega$		25	60	ns
$t_{d(off)}$	Turn-Off Delay Time			8	25	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4, 5)		15	40	ns
Qg	Total Gate Charge	$V_{DS} = 48 \text{ V}, I_{D} = 13 \text{ A},$		5.8	7.5	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 10 V		2.0		nC
Q <sub>gd</sub>	Gate-Drain Charge	(Note 4, 5)		2.5		nC
Drain-S	Source Diode Characteristics a	nd Maximum Ratings				
I <sub>S</sub>	Maximum Continuous Drain-Source Did			10	Α	
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Forward Current				40	Α
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 10 A			1.5	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 13 A,		39		ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F / dt = 100 \text{ A/}\mu\text{s}$ (Note 4)		40		nC

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 990μH, I<sub>AS</sub> = 10A, V<sub>DD</sub> = 25V, R<sub>G</sub> = 25  $\Omega$ , Starting T<sub>J</sub> = 25°C 3. I<sub>SD</sub>  $\leq$  13A, di/dt  $\leq$  300A/us, V<sub>DD</sub>  $\leq$  BV<sub>DSS</sub>, Starting T<sub>J</sub> = 25°C 4. Pulse Test : Pulse width  $\leq$  300μs, Duty cycle  $\leq$  2% 5. Essentially independent of operating temperature

# **Typical Characteristics**

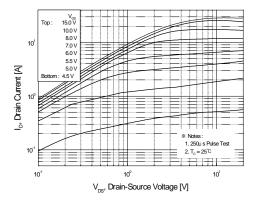


Figure 1. On-Region Characteristics

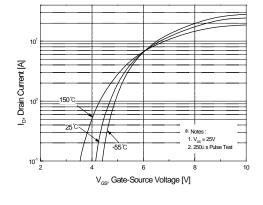


Figure 2. Transfer Characteristics

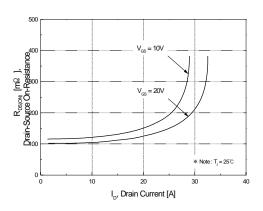


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

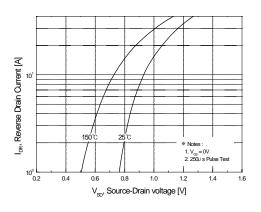


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

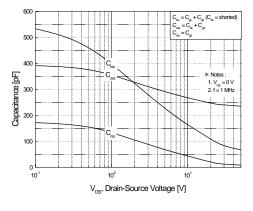


Figure 5. Capacitance Characteristics

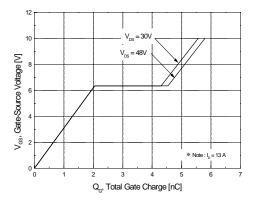
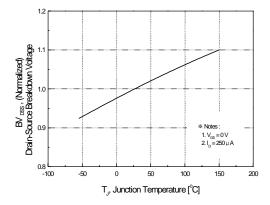


Figure 6. Gate Charge Characteristics

# Typical Characteristics (Continued)



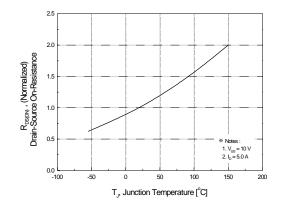
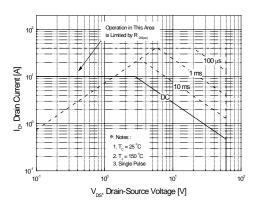


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



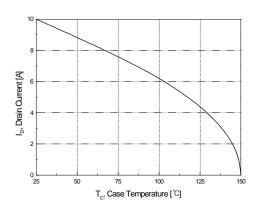


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

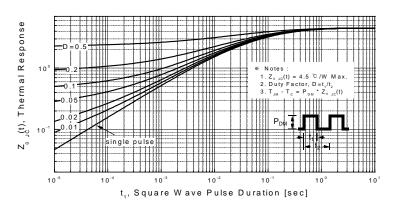
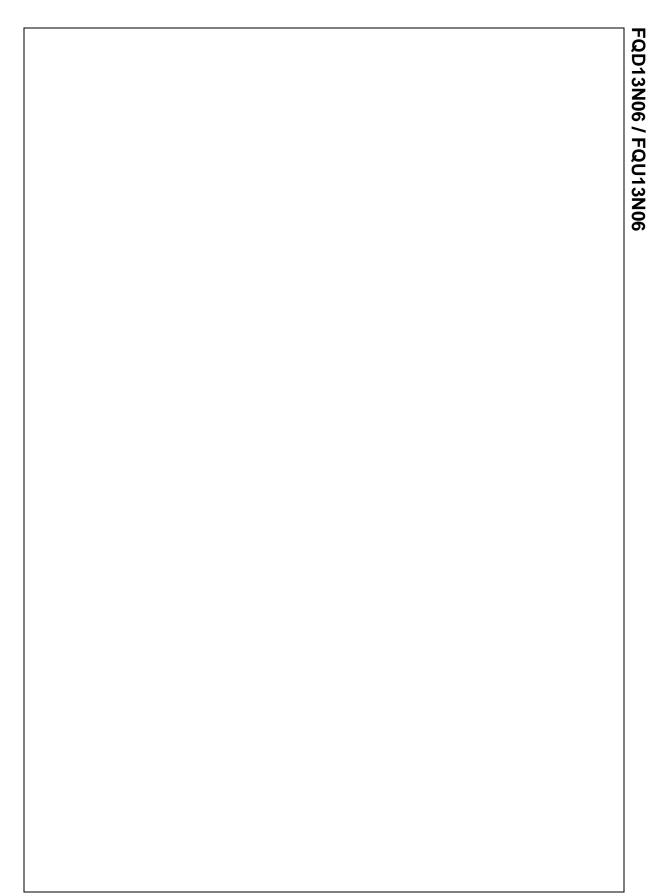
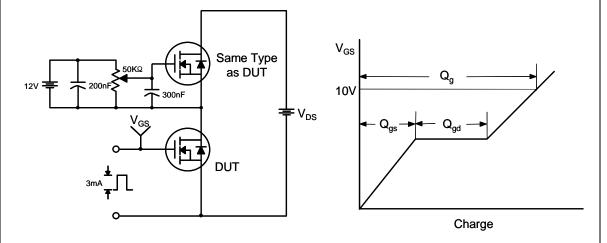


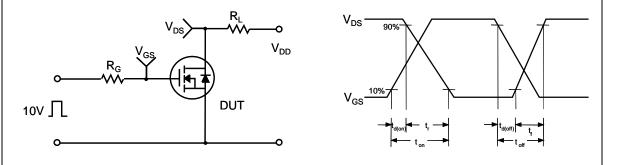
Figure 11. Transient Thermal Response Curve



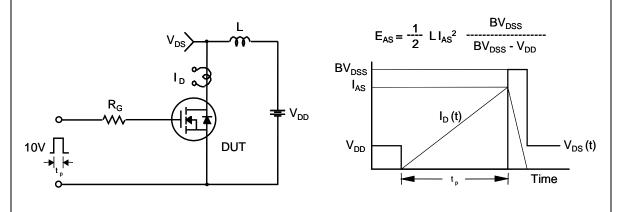
#### **Gate Charge Test Circuit & Waveform**



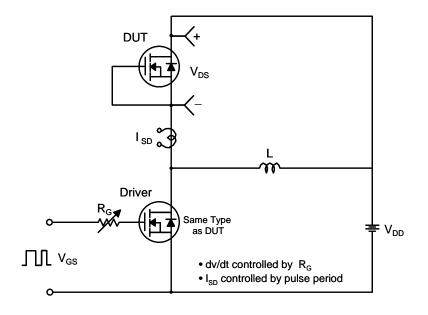
#### **Resistive Switching Test Circuit & Waveforms**

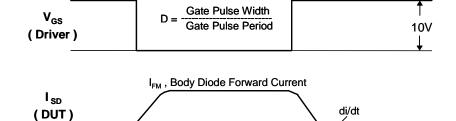


## **Unclamped Inductive Switching Test Circuit & Waveforms**



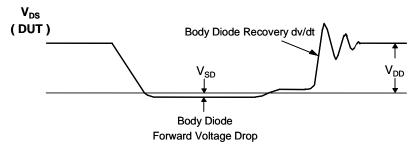
#### Peak Diode Recovery dv/dt Test Circuit & Waveforms

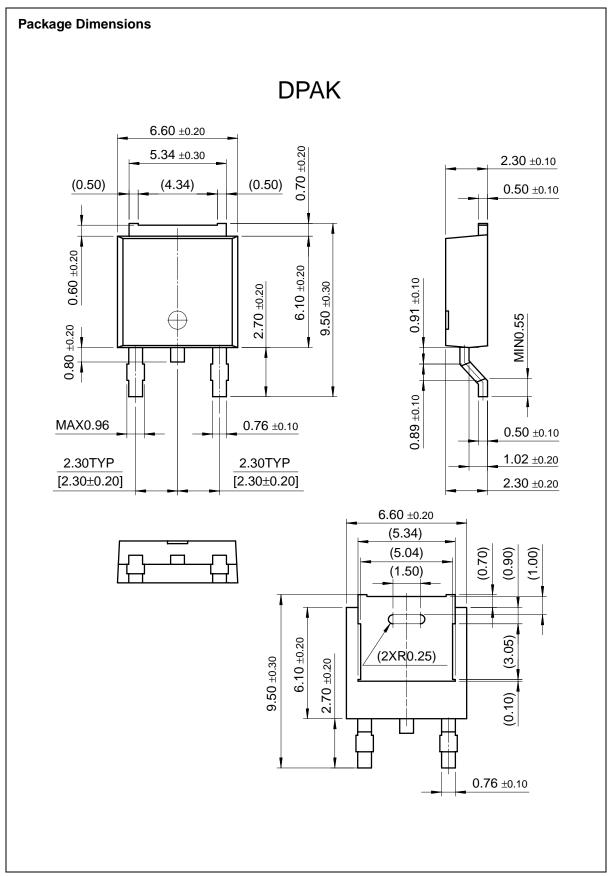




**Body Diode Reverse Current** 

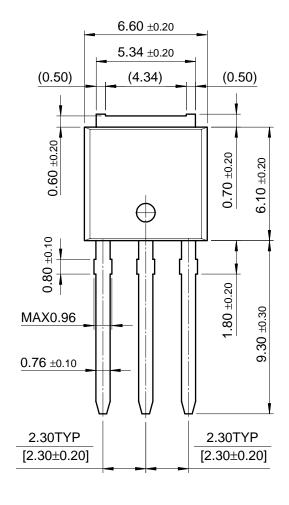
 $I_{RM}$ 

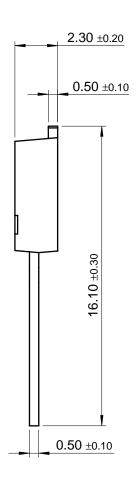


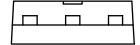




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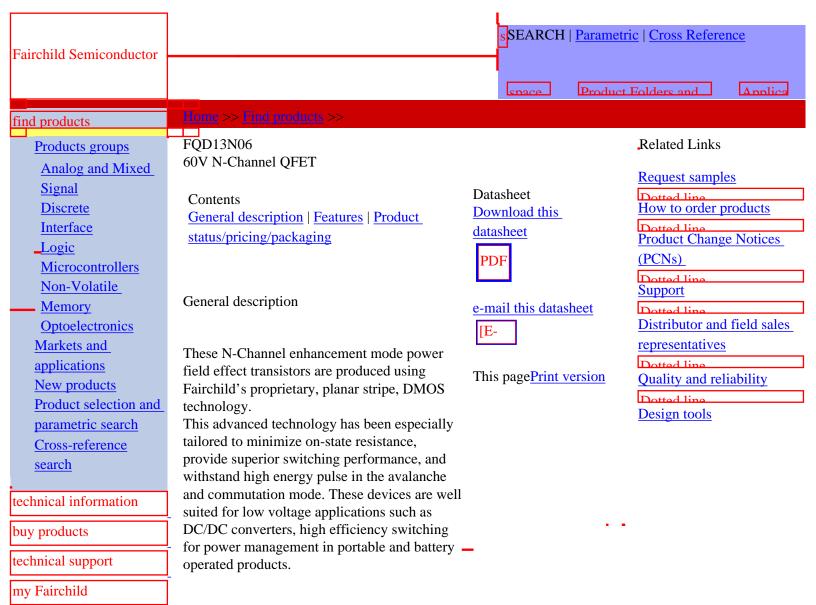
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#### Features

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- 10A, 60V,  $R_{DS(on)} = 0.14\Omega$  @ $V_{GS} = 10$
- Low gate charge (typical 5.8 nC)
- Low Crss (typical 15 pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability

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#### Product status/pricing/packaging

Product	Product status	Pricing*	Package type	Leads	Packing method
FQD13N06TM	Full Production	\$0.367	TO-252(DPAK)	2	TAPE REEL

FQD13N06TF	Full Production	\$0.367	TO-252(DPAK)	2	TAPE REEL
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<sup>\* 1,000</sup> piece Budgetary Pricing

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